

## Qualification and Reliability Report

 Series: EMRA51

Qualification Tests				
Test	Method/Condition	Test	Pass	Fail
Aging	Biased, Nominal V <sub>DD</sub> , Temperature = 85°C, Duration = 30 days	120	120	0
Autoclave	JESD22-A102, 121°C, 100% RH, 15 PSIG, 96 hours	240	240	0
ESD Susceptibility	JESD22-A114, HBM 2000V	3	3	0
	JESD22-C101, CDM 700V	3	3	0
	JESD22-A115, MM 200V	3	3	0
High Temperature Operating Life	JEDS22-A108	240	240	0
High Temperature Storage	JESD22-A103	240	240	0
Highly Accelerated Temperature and Humidity Stress Test	JESD22-A110	240	240	0
Latchup	JESD78, 100mA @ 125°C	24	24	0
Mechanical Dimensions	Per Datasheet	48	48	0
Mechanical Shock	MIL-STD-883 Method 2002 Condition E, 10Kg	120	120	0
Moisture Sensitivity Level	JESD22-A113, MSL = 1, 260°C	180	180	0
Resistance to Solvents	MIL-STD-202, Method 215	120	120	0
Solderability	MIL-STD-883, Method 2003 (Pads on bottom of package only)	120	120	0
Temperature Cycle	JESD22-A104	240	240	0
Thermal Shock	JESD22-A106	180	180	0
Vibration	MIL-STD-883 Method 2007 Condition A, 20G's	120	120	0

Reliability Tests				
Test	Method/Condition	Test	Pass	Fail
Vibration	MIL-STD-883, Method 2007, 20 G's	160	160	0
Mechanical Shock	MIL-STD-883, Method 2002, 1,500G's, 0.5msec, ½ sine	160	160	0
Temperature Cycle	MIL-STD-883, Method 1010, -55°C to +125°C, 10 cycles	160	160	0
Aging	Biased, Nominal V <sub>DD</sub> , Temperature = 85°C, Duration = 720 hours	160	160	0

Reliability Data		
Characteristic	Constant	Value
Number of Units	<i>N</i>	160
Hours Tested	<i>t</i>	1,000
Activation Voltage	<i>Ea</i>	0.7eV
Boltzman's Constant	<i>k</i>	8.62 x 10 <sup>-5</sup>
Aging Temperature	<i>T1</i>	85°C
Ambient Temperature	<i>T2</i>	25°C
Confidence Level	<i>X</i> <sup>2</sup> <sub>(CL, 2 dof)</sub>	90%

Reliability Calculations	
Parameter	Value
Failures in Time (FIT)	15 units / 1 x 10 <sup>9</sup> Hours
Mean Time To Failure (MTTF)	67,175,000 hours / Failure

$$FIT = \frac{(\chi^2 / 2) \cdot 1,000,000,000}{\sum \left[ f_i \cdot t_i \cdot e^{\frac{Ea}{k} \left( \frac{1}{T1+273} - \frac{1}{T2+273} \right)} \right] + \left[ N \cdot t \cdot e^{\frac{Ea}{k} \left( \frac{1}{T1+273} - \frac{1}{T2+273} \right)} \right]}$$

$$MTTF = 1,000,000,000 / FIT$$